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Kaplow, W.K.; Szymanski, B.K.; Tannenbaum, P.; Decyk, V.K.;
Parallel Algorithms/Architecture Synthesis, 1997. Proceedings. Second Aizu International Symposium , 17-21 March 1997
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Thomas, L.A.;

Software Engineering, 2000. Proceedings of the 2000 International Conference on Software Engineering, 11 June 2000

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2 The virtual teleworker-experimenting with a remote software engineering environment
Gautier, R.J.; Thomas, L.A.;

Teleworking and Teleconferencing, IEEE Colloquium on , 1994

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3 Investigation into the causes of browning in EVA encapsulated flat modules
Holley, W.H., Jr.; Agro, S.C.; Galica, J.P.; Thomas, L.A.; Yorgensen, R.S.; Ezri, Klemchuk, P.; Lavigne, G.;

Photovoltaic Energy Conversion, 1994., Conference Record of the Twenty Fourth IEEE Photovoltaic Specialists Conference - 1994, 1994 IEEE First World Conference on Photovoltaic Energy Conversion, Volume: 1 , 5-9 Dec. 1994

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